

**Search Notes**

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Examiner

Nguyen N. Hanh

Applicant(s)/Patent under  
Reexamination

TAKEHARA ET AL.

Art Unit

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**SEARCHED**

Class	Subclass	Date	Examiner
310	90	12/21/2006	HN
310	90.5	12/21/2006	HN
310	156.01	12/21/2006	HN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR